



SIMULATION RESULTS

1) the presence of W plane above the silicon plane cause a "disturbance" on the dE/dX measure of that plane. <u>Nothing to do with nuclear interactions</u>



2) Nuclear spallation cause infficiency and contamination on charge identification











NUCLEAR INTERACTIONS





average of dE in the first 6 Si Layers (3 double planes)

100GeV/n







Without W and PSD Interactions

100GeV/n





quality cut ?













CONCLUSIONS

W between silicon layers disturb the de/dx measurement

1cm PSD above dE/dx measure is more critical than W concerning Nuclear interations effects